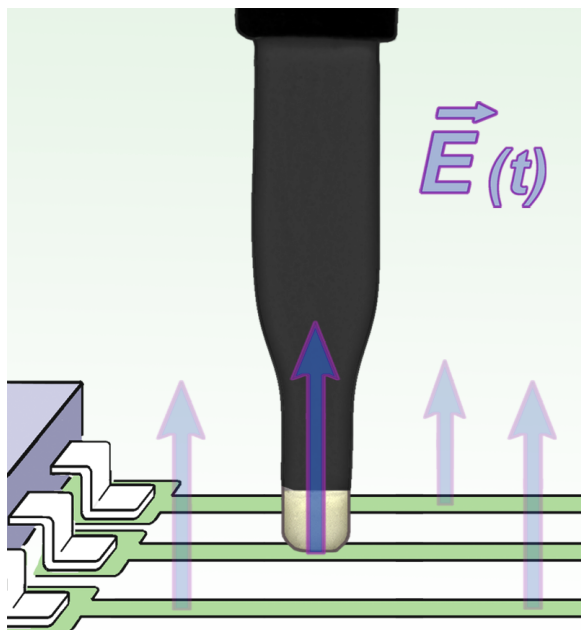


RFS-E 10

Scanner Probe 30 MHz up to 3 GHz

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Short description

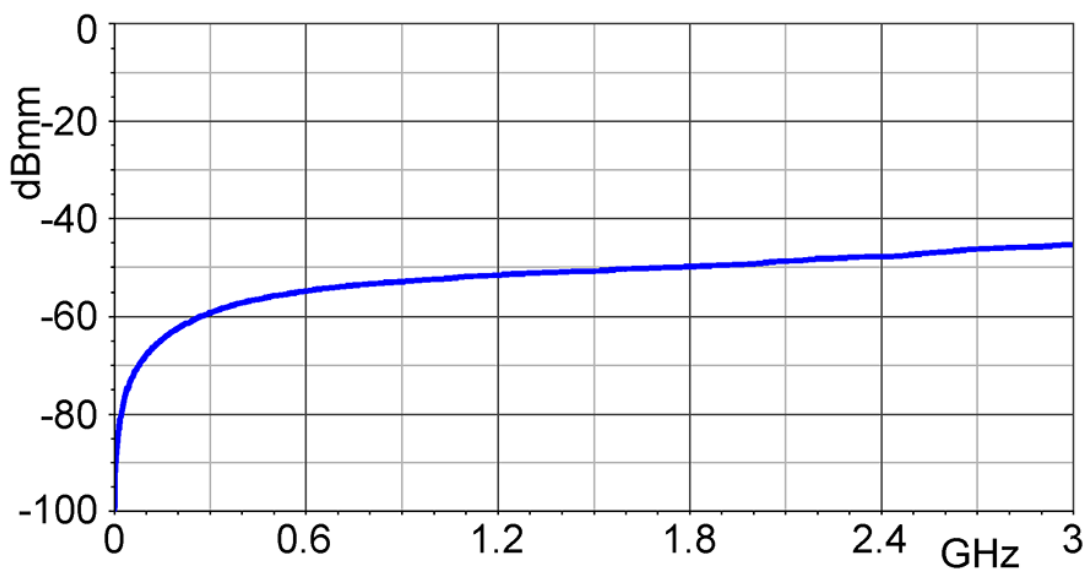
The electrode underneath the RF-E 10 scanner probe head has a width of approx. 0.2 mm, which can locate even the smallest E-field sources, e.g. conducting paths with a width of 0.1 mm or, single IC pins at high pin ICs.

The RFS-E 10 is a passive near-field scanner probe. For measurements the E-field probe is positioned above the components or areas of the PC board. The near-field probe has a sheath current attenuation and is electrically shielded. It can be connected to a spectrum analyzer or an oscilloscope with a 50 Ω input. The E-field probe does not have a 50 Ω terminating resistor internally.

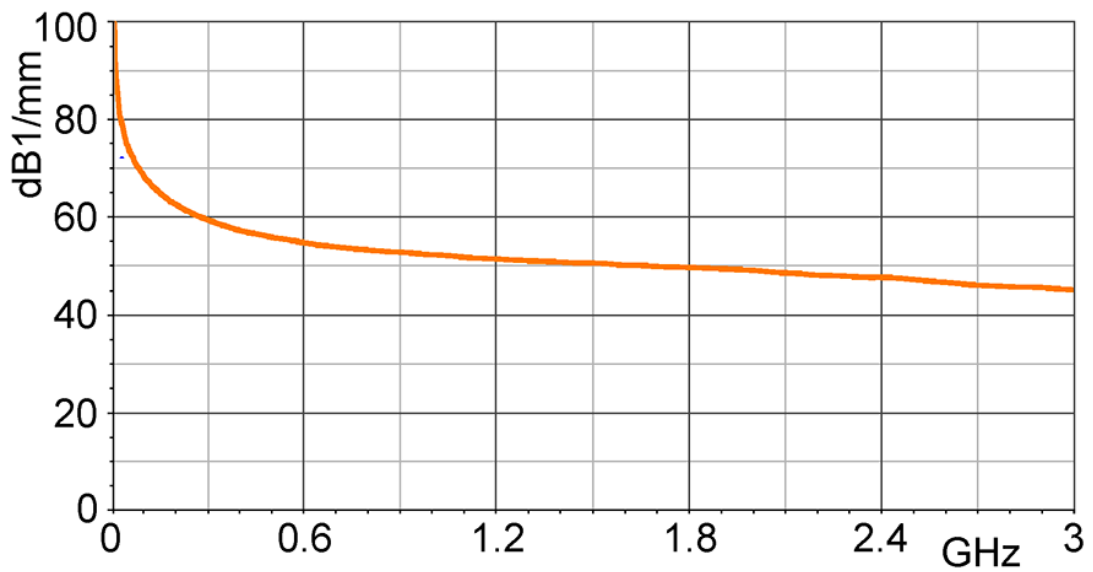
Technical parameters

Frequency range	30 MHz ... 3 GHz
Resolution	≈ 0.2 mm
Probe head dimensions:	$\approx (0.5 \times 2)$ mm
Connector - output	SMA, male, jack

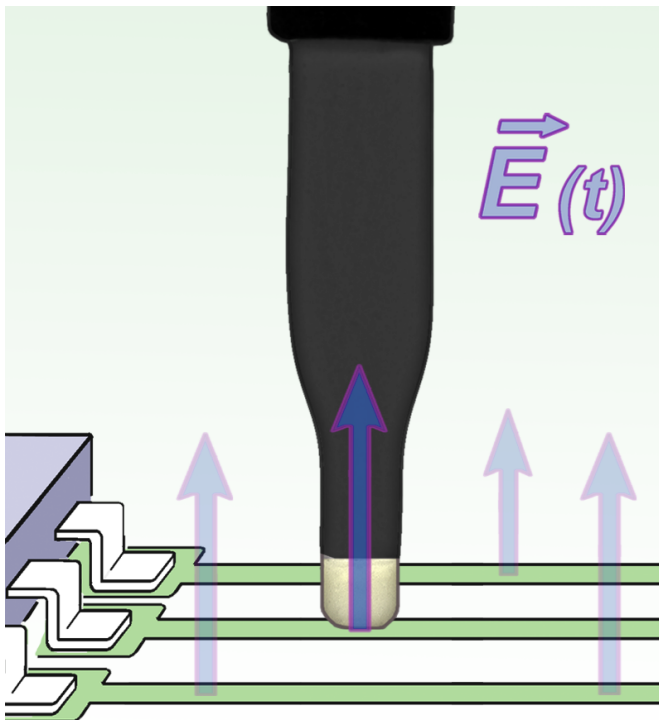
Frequency response [dB μ V] / [dB μ A/m]



E- field correction curve [dB μ V/mm] / [dB μ V]



Measuring principles



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